

IEC SYSTEM FOR CONFORMITY TESTING AND  
CERTIFICATION OF ELECTRICAL EQUIPMENT (IECEE)  
CB SCHEME

SYSTEME CEI D'ESSAIS DE CONFORMITE ET DE CERTIFICATION  
DES EQUIPEMENTS ELECTRIQUES (IECEE)  
METHODE OC

## CB TEST CERTIFICATE CERTIFICAT D'ESSAI OC

Product  
Produit

Bar Code Scanner

Name and address of the applicant  
Nom et adresse du demandeur

Microscan Systems Inc  
1201 SW 7th St  
Renton, WA 98057, USA

Name and address of the manufacturer  
Nom et adresse du fabricant

Microscan Systems Inc  
1201 SW 7th St  
Renton, WA 98057, USA

Name and address of the factory  
Nom et adresse de l'usine

Microscan Systems Inc  
1201 SW 7th St  
Renton, WA 98057, USA

Rating and principal characteristics  
Valeurs nominales et caractéristiques principales

10-28 Vdc, 3.6 W

Trademark (if any)  
Marque de fabrique (si elle existe)

Not applicable

Model / Type Ref.  
Ref. de type

MS-800 and MS-820

Additional information (if necessary)  
Information complémentaire (si nécessaire)

This CB Test Report comprises 5 enclosures.

A sample of the product was tested and found  
to be in conformity with  
Un échantillon de ce produit a été essayé et a été  
considéré conforme à la

### PUBLICATION

### EDITION

**IEC 60950-1 (2001) First Edition,**  
Additional evaluation to CENELEC Common Modifications also included.  
See Test Report for National Differences.

as shown in the Test Report Ref. No.  
which forms part of this Certificate  
comme indiqué dans le Rapport d'essais numéro  
de référence qui constitue partie de ce Certificat

E137142-A8-CB-2

This CB Test Certificate is issued by the National Certification Body  
Ce Certificat d'essai OC est établi par l'Organisme National de Certification

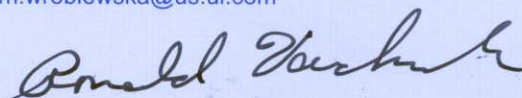


**Underwriters  
Laboratories**

Underwriters Laboratories Inc. / Certification Programs Office, USA  
333 Pfingsten Road, Northbrook, IL 60062-2096  
United States of America  
TEL INT\* +1 847 664 3008, FAX INT\* +1 847 313 3008  
email: jolanta.m.wroblewska@us.ul.com

Date: Issued: 2009 May 6

Signature:



Ronald Vaickauski